Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/724,169	PARK ET AL.
Examiner	Art Unit
Tianjie Chen	2627

	SEAR	CHED	
Class	Subclass	Date	Examiner
720	650		
360	97.01		
361	749		
369	116		
200	305	6/16/2006	TJ

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East Reports	5/16/2006	TJ	